PATENT NUMBER

U.S. UTILITY Patent Application

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SCANNED	711	

PATENT DATE

PLICATION NO. CONT/PRIOR CLASS SUBCLASS ART UNIT EXAMINER 109/586692 356 451 2877 TUNIEL

Martin Debreczeny Michael O'Neil

Dual beam FTIR methods and devices for use in analyte detection in samples of low transmissivity

PTO-2040 12/99

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	ISSUING	CLASSIFICATION			
ORIGINAL	CROSS REFERENCE(S)				
CLASS SUBCLASS	CLASS SUBCLASS (ONE SUBCLASS PER BLOCK)				
356 451					
INTERNATIONAL CLASSIFICATION					
6018 9/02		10109			
	/				
		Continued on Issue Slip Inside File Jacket			

TERMIN!	1	DRAWINGS		CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
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of U.S Patent. No.	Primary	al A. Turner y Examiner	5-11-05	Amount Due	Date Paid
The terminal _ this patent have be	02/	(Primary Examiner) (Date)		ISSUE BATCH NUMBER	
WARNING: The information disclosed herein possession outside the U.S. Pater					Title 35, Sections 122, 181

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